Assessment of an extended Nijboer–Zernike approach for the computation of optical point-spread functions

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We assess the validity of an extended Nijboer–Zernike approach [J. Opt. Soc. Am. A 19, 849 (2002)], based on recently found Bessel-series representations of diffraction integrals comprising an arbitrary aberration and a defocus part, for the computation of optical point-spread functions of circular, aberrated optical systems. These new series representations yield a flexible means to compute optical point-spread functions, both accurately and efficiently, under defocus and aberration conditions that seem to cover almost all cases of practical interest. Because of the analytical nature of the formulas, there are no discretization effects limiting the accuracy, as opposed to the more commonly used numerical packages based on strictly numerical integration methods. Instead, we have an easily managed criterion, expressed in the number of terms to be included in the Bessel-series representations, guaranteeing the desired accuracy. For this reason, the analytical method can also serve as a calibration tool for the numerically based methods. The analysis is not limited to pointlike objects but can also be used for extended objects under various illumination conditions. The calculation schemes are simple and permit one to trace the relative strength of the various interfering complex-amplitude terms that contribute to the final image intensity function. © 2002 Optical Society of America

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1. INTRODUCTION

In optical imaging, an exact knowledge of the optical impulse response or point-spread function is required for the calculation of the image intensity pattern in the presence of more complicated objects. Analytical expressions for the point-spread function are available in some simple cases if the wave front exiting from the exit pupil is spherical and the transmission function of the optical system is uniform over a certain region (e.g., an annular pupil). In all other cases, numerical approaches based on integration of the complex amplitude over the exit pupil area are used.

An analytical expression for the impulse response in the aberration-free case for an out-of-focus position has been provided for the first time by Lommel (see Ref. 1, Sec. 8.8). The impulse response in the presence of (small) aberrations has been studied by Nijboer and Zernike, who used orthogonal expansions involving Zernike polynomials to evaluate the impulse response. Their approach poses problems if the wave-front aberration function \( W \) approaches values in excess of \( \lambda/4 \), say \( \lambda \), because of the appearance of products of Zernike polynomials in the higher-order expansion terms; such products seemed rather intractable at that time. We remind the reader that the Nijboer–Zernike theory is an approximation for moderate values of the numerical aperture (NA), not significantly larger than a value of 0.60. Beyond this value, the quadratic approximation to the path-length difference occurring in the exponential of the integrand of the diffraction integral is questionable. In Appendix A, we present the higher-order wave-front terms that are needed for a correct representation of defocusing in high-aperture systems. With this extension, the path length due to defocusing is correctly accounted for if the NA value approaches 0.90. However, beyond the value of 0.70, a more rigorous treatment involving the state of polarization of the focusing wave is needed. The polarization-dependent effects become clearly visible at aperture values as large as 0.8. In this paper, we will limit ourselves to the scalar diffraction integral, although an extension to the vectorial case is possible along the lines of our analysis, the number of integrals to be evaluated then being six (three for each orthogonal polarization state) instead of one.

The basic scalar diffraction integral to be evaluated for obtaining the spatial impulse response \( U(x, y) \) in image space reads as (see Ref. 1, Sec. 9.1)
toward the image plane (center at $P_0$). The diameter of the exit pupil is $2\rho_0$, and the distance from pupil to image plane is $R$. The real-space image-plane coordinates are $(X, Y)$. In this paper, the exit pupil coordinates are normalized to unity by means of the value of $\rho_0$, and denoted by $(\nu, \mu)$; the image-plane coordinates are normalized with the aid of the diffraction unit $\lambda/NA$ and denoted by $(x, y)$. $NA (=\rho_0/R)$ is the image-side numerical aperture of the optical system.

Here the amplitude transmission function $A(\nu, \mu)$ has been put equal to unity. Next, the aberration function $\Phi$ is represented as

$$\Phi(\rho, \theta) = \sum_{n,m} \alpha_{nm} R_n^m(\rho) \cos m \theta,$$

where $R_n^m(\rho)$ are the Zernike polynomials. The expansion in Eq. (3) is in terms of orthogonal functions $R_n^m(\rho) \cos m \theta$ on the unit circle and contains only terms with integers $n, m \geq 0$ such that $n - m$ is even and $\geq 0$. When aberrations are small, so that truncation of the infinite series in Eq. (2) after the term with $k = 1$ is allowed, we get (using elementary properties of Bessel functions), to a good approximation,

$$U(x, y) \approx 2 \int_0^1 \rho \exp(ifp^2) J_0(2\pi \rho r) d\rho$$

$$+ 2i \sum_{n,m} i^n \alpha_{nm} \int_0^1 \rho \exp(ifp^2) R_n^m(\rho) \times J_m(2\pi \rho r) d\rho \cos m \phi.$$  

The reduction of the integrals in relation (4) is rather cumbersome. The method proposed by Nijboer, see Ref. 1 (Sec. 9.4) and Ref. 3, is based on the expansion of $\exp(ifp^2)$ as a series involving Zernike polynomials. The method requires an ad hoc procedure for representing products of two Zernike polynomials as a finite linear combination of Zernike polynomials with a prescribed upper index $m$. Finally, the basic identity

$$\int_0^1 \rho R_n^m(\rho) J_m(2\pi \rho r) d\rho = (-1)^{n-m/2} J_{n+1}(2\pi r)$$

is applied. However, to the knowledge of the authors, the method of representing products of Zernike polynomials has remained mainly in a guess-and-try stage and thus yields useful results only for relatively small values of $n$ and $m$. This problem becomes even more serious when first-order considerations as in relation (4) no longer suffice, so that products of more than two Zernike polynomials occur, as a result of terms on the right-hand side of Eq. (2) with $k \geq 2$ that must be included. For these reasons, the Nijboer–Zernike theory is not satisfactory when aberrations and defocus values are considered that have values of order unity or larger.

A different approach, yielding valid results when the defocus parameter is large, consists in applying certain methods from asymptotic analysis. These methods are of limited use when one is interested in accurate computation of the point-spread functions, especially when $f$ is neither very small nor very large. For the latter cases, it has become common practice to compute the integrals in Eq. (1) and/or (2) by using strictly numerical integration methods. In these numerical methods, one has inevitably to cope with the problem of selecting integration grids, preferably covering a square region in the $(\nu, \mu)$ plane, so as to be able to take advantage of the computational efficiency of fast Fourier transforms, (FFTs), to approximate integrals of functions that are inherently discontinuous (viz., at the edges of the pupil $\nu^2 + \mu^2 \leq 1$). In the frequently occurring cases in which one uses a commercial
software package for evaluating diffraction integrals [e.g., SOLID-C (Ref. 5)], one has, furthermore, normally only limited access to the source codes, and hence a quality assessment of the obtained results is not feasible. Moreover, the result produced by these software packages is the image intensity distribution, whereas a knowledge of the complex-amplitude terms yields a more profound understanding of the final result.

In this paper, we propose to use the analytical formulas of the Lommel type that were found in Ref. 4 for integrals as they occur in relation (4), and for integrals similar to those in relation (4), with $R_n^m(p)$ replaced by the monomial $p^m$, where $n - m \geq 0$ and even. As explained in Ref. 4, Sec. 3, any of the integrals involving $\Phi^B$ in Eq. (2) can be reduced to a finite sum of integrals of the type just mentioned, whence we have an analytical means to calculate $U(x, y)$. Alternatively, one may find it feasible to develop the complete complex pupil function $A\exp(i\Phi)$ in Eq. (1) in terms of Zernike polynomials, and then we are in a position similar to that of relation (4).

In this new approach, the through-focus calculation of the point-spread function becomes feasible for much larger values of the wave-front aberration function than in the Nijboer–Zernike approach; both the defocus parameter and the aberration term may assume values comparable with or even larger than $2\pi$ in terms of the induced phase aberration without compromising the accuracy. Of course, the analysis extensively uses the properties of Zernike polynomials and supposes a circular geometry for the exit pupil. However, in principle, nonuniform amplitude distributions are permitted, and therefore a noncircular pupil rim or a central obstruction could be accommodated, albeit at the expense of an increased number of higher-order terms in the expansion. In the analysis presented in this paper, the azimuthal dependence of the Zernike polynomials is limited to a cosine dependence. An extension to a general orientation of the wave-front aberration can easily be included. Even with this extension, the calculation scheme according to our analysis remains very short, and its implementation into a symbolic program is easily realized.

This paper is organized as follows. In Section 2, the basic formulas are presented that are needed to treat the various practical examples in the subsequent sections. In Section 3, we present interpretations of our basic formulas in optical terms; this comprises a comparison of the formulas in the in-focus and defocused cases, symmetry properties of the image intensity distribution, and considerations about the radial extent of the impulse responses. In Section 4, we consider computational aspects of our method, such as a verification of the convergence analysis developed in Appendix B and some basic problems concerning Zernike expansions as in relation (4). We also present in Section 4 a numerical comparison of our method with strictly numerical methods, such as those embodied by software packages. In Section 5, we study the imaging of an extended object for various coherence conditions; the impulse response approach clearly shows the separate origin of the background intensity terms and the coherence-based term of the intensity pattern. Finally, in Section 6, we apply our analysis to high-frequency aberration terms corresponding to a scattering type of image blur. This type of unsharpness is present in multicomponent optical systems with many glass–air transitions; it also plays a role in imaging through turbulent media, e.g., astronomical observation through the atmosphere. We will show that the impulse response approach to this type of blurred imaging is very robust and does not suffer from the numerical stability problems associated with the standard approach. Finally, in Appendix A, we analyze the defocusing term in the case of a high-NA system, and we present the expression for the coefficients of higher-order radial Zernike polynomials, which have to be included in this case. In Appendix B, the maximum absolute value of the terms in the series expansion for the impulse response is given, and a convergence criterion for the required number of terms in the series expansion is developed.

2. BASIC FORMULAS FOR THE COMPUTATION OF $U(x, y)$

In this section, we present the basic formulas to be used for the computation of $U$ in the examples in the following sections. We start by expanding a general pupil function $A\exp(i\Phi)$ in terms of Zernike polynomials as

$$A(\rho, \theta)\exp[i\Phi(\rho, \theta)] = \sum_{n,m} \beta_{nm} R_n^m(\rho) \cos m \theta,$$

(6)

with coefficients $\beta_{nm}$ ($n \geq m \geq 0, n - m$ even) that are complex in general. The expansion in Eq. (6) of $A\exp(i\Phi)$ can be obtained, for instance, by a least-squares fit of a finite series with sufficiently many terms to a (measured) pupil function $A\exp(i\Phi)$, a procedure that is common practice for expanding $\Phi$ itself. The efficient and reliable calculation of the coefficients $\beta_{nm}$ for a general pupil function $A\exp(i\Phi)$ is still under study and will be treated in more detail in a forthcoming publication. It can be shown that the field $U$ as defined by relation (4) is given by

$$U(x, y) = 2 \sum_{n,m} \beta_{nm} i^m V_{nm} \cos m \phi,$$

(7)

where

$$V_{nm} = \int_0^1 \rho \exp(if\rho^2) R_n^m(\rho) J_m(2\pi \rho r) d\rho,$$

(8)

for integers $n, m \geq 0$ with $n - m \geq 0$ and even. The Bessel-series presentation for $V_{nm}$ has been given in Ref. 4 and reads as

$$V_{nm} = \exp(if) \sum_{l=1}^{\infty} (-2if)^l \sum_{j=0}^{-p} v_{lj} \frac{J_{m+i+2j}(u)}{l!},$$

(9)

with $v_{lj}$ given by

$$v_{lj} = (-1)^p (m + l + 2j) \binom{m + j + l - 1}{l - 1} \binom{j + l - 1}{l - 1} \binom{l - 1}{p - j} \binom{q + l + j}{l + j},$$

(10)

where $l = 1, 2, \ldots, j = 0, \ldots, p$. In Eqs. (9) and (10) we have set
where \( l = 1, 2, \ldots, j = 0, \ldots, p \). The truncation rule for the Bessel-series representations of \( T_{nm} \) is the same as that for the corresponding representations of \( V_{nm} \) [see relations (12)].

For the case in which a second- or higher-order approximation of \( U \) is required, one can establish formulas that, unfortunately, become rather complicated for increasing values of \( k \). In certain special cases, such as

\[
\Phi(\rho, \theta) = \alpha \rho^5 \cos \theta, \quad \gamma \rho^2 \cos 2\theta, \quad \delta \rho^4,
\]

which represent (uncorrected) coma, astigmatism, and fourth-order spherical aberration, respectively, a considerable shortcut of the general program is possible. In Ref. 4, Sec. 4, such a thing is done for the first two cases in Eqs. (18), and this yields expansions

\[
U(x, y) = \sum_{j=0}^{\infty} C_j \alpha^j, \quad \sum_{j=0}^{\infty} D_j y^j,
\]

with \( C_j, D_j \) expressed explicitly in terms of the coefficients \( T_{nm} \) in Eq. (15). In Section 4, we shall use such an expansion for the third case (spherical aberration).

3. PHYSICAL INTERPRETATION OF THE BASIC FORMULAS

In this section, we show, starting from the aberration-free case, how the complex amplitude of an aberrated impulse response is built up from various interfering terms. We consider in this section the case in which the aberration phase \( \Phi \) has been expanded in a Zernike series as in Eq. (3), with \(|\Phi| \) sufficiently small so that linearization as in relation (13) is allowed. The explicit form in Eq. (9) of the \( V_{nm} \) on the right-hand side of Eq. (7) shows a clear separation between the defocusing through powers \( f^{l-1} \) of \( f \) and the radial dependence through finite series involving Bessel functions \( J_{m+l+2j}(v) \) evaluated at the argument \( v = 2\pi r \). Finally, the azimuthal dependence in the series in Eq. (7) is represented by the factors \( \cos m\phi \). Evidently, a separation of variables as we have here has advantages, both in terms of physical interpretation and from a computational point of view.

Before presenting our observations on the through-focus response of an aberrated optical system, we briefly recall the relationship between our normalized image-plane coordinates \((x, y)\) with defocus parameter \( f \) and the real-space image coordinates \((X, Y, Z)\) in the lateral and axial directions:

\[
x = X \frac{\text{NA}}{\lambda}, \quad y = Y \frac{\text{NA}}{\lambda},
\]

\[
v = 2\pi \sqrt{x^2 + y^2}, \quad f = 2\pi Z (1 - \sqrt{1 - \text{NA}^2}).
\]
In Appendix A, it is shown that, in the case of systems with a high numerical aperture the defocus term can be thought to be composed of a quadratic term and a term, represented by radial Zernike polynomials $R_{2n}^0$ with $n \geq 2$, that can be incorporated into the aberration phase.

**A. Impulse Response in Focus ($f = 0$)**

With reference to relation (4) and Eq. (5), the aberration-free case with $f = 0$ leads to the well-known Airy function

$$U(x, y) = \frac{J_1(v)}{v}. \tag{21}$$

The central spot is surrounded by a dark ring, corresponding to the first minimum of $J_1(v)$. The in-focus amplitude distribution in the presence of small aberrations has already been given by Nijboer$^3$. Using the identity in Eq. (5), we obtain the following for small aberrations:

$$U(x, y) \approx 2 \left[ \frac{J_1(v)}{v} \right] + \sum_{n,m} i^{m+1} a_{nm} (-1)^{(n-m)/2} \frac{J_{n+1}(v)}{v} \cos m\phi. \tag{22}$$

**B. Impulse Response in the Presence of Defocus ($f \neq 0$)**

In this subsection, we concentrate on the physical interpretation of the quantities $V_{nm}$ when $f \neq 0$ and the aberration is small.

The out-of-focus impulse response of a slightly aberrated optical system can be written from relation (13) as

$$U(x, y) \approx 2 \left[ V_{00} + \sum_{n,m} i^{m+1} a_{nm} V_{nm} \cos m\phi \right], \tag{23}$$

where, as in the series in relation (22), the summation indices $n, m \geq 0$ and $n - m \geq 0$ and even. The quantities $V_{nm}$ depend on $f$ and $v$ as shown in Eq. (9), with appropriate coefficients $v_{ij}$ as given in Eq. (10). The close resemblance between relation (22) and (23) stems from the representation of $U$ in the defocused case in terms of the functions $V_{nm}$ that substitute for the functions $(-1)^{(n-m)/2} J_{n+1}(v)/v$ in the in-focus situation. It is easily verified [see Eqs. (5), (9), and (10)] that for $f = 0$, the functions $V_{nm}$ reduce to the corresponding expressions comprising the Bessel functions of order $n + 1$.

The above formulas for $U(x, y)$ also lead to the symmetry properties for the intensity $I(x, y) = |U(x, y)|^2$, which were already enumerated in Ref. 1, Chap. 9.4, and which we briefly recall for a single aberration term $a_{nm} R_n^m(p) \cos m\phi$:

- The vertical axis is an $m$-fold symmetry axis; in particular, for $m = 0$ circular symmetry is present.
- When $m$ is odd, the plane $z = 0$ is a symmetry plane.

We finally remark that the formulas also yield a good estimate of the radial extent of the impulse response once the maximum order of the radial Bessel function has been established. The first zero of the Bessel function of order $n$ is found at a coordinate value given by $v = n + 3$, and this yields an estimate of the lateral extent of the aberrated point-spread function. For low argument values, the function $J_1(v)$ of order $n$ is proportional to $v^n$. In this respect, it is interesting to note that in the presence of nonzero values of $m$, the expressions for $V_{nm}$ [Eq. (9)] and $T_{nm}$ [Eq. (16)] contain Bessel functions with a minimum index value of $n + 1$. This value $n + 1$ indicates that the contribution to the total amplitude of the point-spread function is small for low $v$ values and that the spread (typically to a $u$ value of $m + 4$) of the impulse response increases when the azimuthal index $m$ of the coefficients $a_{nm}$ or $b_{nm}$ becomes larger.

In Fig. 2, we have presented the function $V_{nm}$ for various combinations of $n$ and $m$ and, in each case, for defocus parameter values 0 and $\pi$. Both the real and imaginary parts of $V_{nm}$ have been displayed, as well as its modulus squared, $|V_{nm}|^2$, which corresponds to the image-space intensity when only the single aberration term $R_n^m(p) \cos m\phi$ is present.

**4. COMPUTATIONAL ASPECTS AND NUMERICAL COMPARISON**

In this section, we restrict ourselves to the scalar diffraction integral with the resulting impulse response given by Eq. (1). We first give a number of computational considerations concerning the series representations in Eq. (9). As an example, we consider the case in which the aberration $A \exp(i\Phi)$ is given as

$$A = 1, \quad \Phi(p) = \alpha_{4.0} R_4^0(p) = \frac{2\pi}{6} (6p^4 - 6p^2 + 1), \quad 0 \leq p \leq 1, \tag{24}$$

and we present specific convergence results for $V_{4.0}$. Next, a comparison of our method with strictly numerical methods is made from a numerical point of view. Again, we take Eqs. (24) as an example. The coefficient $\alpha_{4.0}$ in Eqs. (24) is chosen to be $2\pi/6$, since this corresponds to the "just"-diffraction-limited case in the best-focus position.

**A. Computational Aspects**

We start by verifying the rule of thumb developed in Appendix B that the number $L$ of terms that should be in-
included in Eq. (9) for accuracy $10^{-4}$ should be of the order of $3f$. In Table 1, we present the quantity

$$\max_{|v|<30} |V_{4,0}(L)|^2 - |V_{4,0}(40)|^2,$$

with $f = 2\pi$ as a function of $L$. Here $V_{4,0}(L)$ is the right-hand-side series in Eq. (9), truncated after $L$ terms; we take $V_{4,0}(40)$ as a reference.

As to the computation of the coefficients $v_{ij}$ and the Bessel functions $J_n(v)$ that occur on the right-hand side of Eq. (9), we have the following comments. For low values of $l$ and $j$, we can use the binomial function "choose $k$ from $n$" since we have presented the $v_{ij}$ as a combination of binomials. For the case in which $v_{ij}$ is needed for very

<table>
<thead>
<tr>
<th>$L$</th>
<th>Maximum Intensity Difference</th>
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<tr>
<td>10</td>
<td>$5.0 \times 10^5$</td>
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<tr>
<td>15</td>
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<td>$8.4 \times 10^{-5}$</td>
</tr>
<tr>
<td>25</td>
<td>$7.2 \times 10^{-8}$</td>
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<tr>
<td>30</td>
<td>$5.1 \times 10^{-11}$</td>
</tr>
<tr>
<td>35</td>
<td>$7.7 \times 10^{-15}$</td>
</tr>
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Table 1. Convergence of the Analytically Calculated Image Intensity $I(x, y) = |U(x, y)|^2$ As a Function of the Number of Terms $L$ Included in the Series Expansion for the Amplitude $U$ (Interval $|v| \leq 30$)
large values of \( l \) and \( j \) (we have not seen such large values in our simulations), we may note that [see Eq. (10)]

\[
B(l; a, b, c, d) := \frac{(a + l - 1)(b + l - 1)(l - 1)}{l - 1} \frac{1}{c} \frac{1}{l} \]

(26)

satisfies the recursion

\[
B(l + 1; a, b, c, d) := \frac{(l + 1)(a + l)(b)}{l(l - c)(l + d + 1)} B(l; a, b, c, d).
\]

(27)

For the computation of the Bessel function, one can use the recursion formulas as given in Ref. 6, expression 9.1.27 on p. 361 (when these are not already present in the software environment of the user).

A further issue is the computation of the coefficients \( \beta_{nm} \) in the expansion

\[
A(p, \theta) \exp[i \Phi(p, \theta)] = \sum_{n,m} \beta_{nm} R_n^m(p) \cos m \theta.
\]

(28)

We are currently in the process of investigating methods to do this accurately and efficiently; see, for instance, Ref. 7.

Consider the example of spherical aberration in Eqs. (24). We have an analytical expression for \( U(x, y) \), in this case in terms of the \( T_{nm} \) of Eqs. (15)–(17); this expression follows, in a similar fashion, the explicit expressions in Ref. 4, Sec. 4, for coma and astigmatism [also see Eqs. (18) and (19)]. It holds that

\[
U(x, y) = 2 \exp(i \alpha_{4,0}) \sum_{k=0}^\infty \frac{(6i \alpha_{4,0})^k}{k!} T_{4k,0},
\]

(29)

where the \( T_{4k,0} \) are computed with defocus parameter \( f - 6 \alpha_{4,0} \) instead of \( f \). Using a simple least-squares-fit method, where we included on the right-hand side of Eq. (28) all terms involving \( R_{2n}^m(p) \) with \( n \leq N \), we found the following result. The maximum intensity deviation for values of \( f \) equal to \(-2\pi, 0, \) and \(+2\pi\), according to

\[
\max_{|c|<30} ||U|^2 - |U_N|^2||,
\]

(30)

where the index \( N \) refers to the number of included terms in Eq. (28), decreases to a level of \( 10^{-8} \) for \( N = 6 \) (the maximum degree \( n \) is limited to 12). Hence we see a quite satisfactory \( 10^{-8} \) accuracy with a relatively modest number of terms on the right-hand side of Eq. (28).

B. Comparison with Strictly Numerical Methods

In this subsection, we present the results of a comparison of our method and two purely numerical methods to evaluate \( U \). For this comparison, we consider the example in Eqs. (24), and we use the analytical formula in Eq. (29) or the \( U_N \) of expression (30) with \( N = 6 \) (the latter \( U_N \) can be identified with the true \( U \) for the present purposes; see the end of Subsection 4.A). A comparison purely in terms of CPU time is not feasible at this moment, since we are still investigating methods for the accurate and efficient determination of the \( \beta_{nm} \). Therefore we focus here on different aspects of such a comparison.

There are the following advantages of our method:

1. The representation of \( U \) as a series in Eq. (7) with the \( V_{nm} \) as given in Eqs. (8)–(10) yields a certain physical interpretation as well as computational advantages (see the beginning of Section 3).

2. The \( U \) obtained in our method is the complex amplitude of the response of the system when a true delta function has been presented as input. Software packages normally deliver intensities and use finite-extent “delta” functions.

3. Aside from the issue of how many terms should be included in the series in Eq. (7), the computation of the terms themselves can be done with a prescribed accuracy by using the convergence analysis (the 3\( f \) rule) of Appendix B. The source codes of a (commercial) package are normally not readily available, whence a quality assessment is more difficult here.

4. Our codes are relatively simple.

We have computed \( I(x, y) = |U(x, y)|^2 \) with the aberration term given by Eqs. (24) and \( f = 0 \) and \( \pm 2\pi \) by using a typical integration procedure based on a set of grid points on a polar mesh in the pupil. With the number of grid points \( N_g \) equal to \( 10^5 \), the intensity values differed by \( 5 \times 10^{-5} \) from the true ones, proving the limitation of the general-purpose strictly numerical method to an accuracy on the order of \( 1/N_g \). Figure 3 illustrates this result by means of the dashed curve [analytical result; see Eq. (29)] and the curve with the open circles (strictly numerical method), which both apply to the true delta function response. The maximum difference of approximately \( 10^{-4} \) between both curves is not visible in the figure.

A second comparison was made by using the software package SOLID-C (Ref. 5), a frequently used simulation tool for optical imaging in lithography. As noted in advantage 2 above, we have to consider an extended object, and for this we take a rectangular contact hole with side lengths of 300 nm in an opaque mask. Recalling our conventions as given by Eqs. (20), we have chosen a wavelength \( \lambda = 248 \) nm, \( NA = 0.20 \), the aberration \( A \exp(i\Phi) \) is that of Eqs. (24), and the defocus parameter equals \( f = -2\pi, 0, 2\pi \). In our method, we must convolve the complex impulse response \( U \) with the step function \( C \) that assumes the value 1 in the contact hole and 0 outside it. We have carried out this convolution by filling the contact hole with \( m^2 \) points \( (m = 3, 5, 9, 15, 25, 50) \). The effect of using 625 instead of 225 points was noticeable for the intensity level. In Fig. 3, we have displayed cross sections of the intensity profiles \( |U \circ C|^2 \), where \( C \) is the step function describing the contact hole, \( \circ \) denotes convolution, and the intensity is obtained by the SOLID-C software package (all intensity levels have been normalized to unity, the on-axis value for the in-focus, aberration-free case). Inspection of the computed data shows that the deviations between the analytically based calculations and the SOLID-C results are of the order of 0.001–0.002; the curves in Fig. 3 show this difference (drawn curves for the analytically based computation and
open squares for the SOLID-C results). The deviation of the SOLID-C results is most pronounced at low $v$ values.

5. IMAGE FORMATION BY AN EXTENDED OBJECT

In the case of image formation by an extended object, the illumination mode of the object plays an important role. For the general case of an object $F(x_0, y_0)$, illuminated in a partially coherent way, the intensity distribution in the image plane is given by

$$I(x, y) = \int \int \int \int \int \mu(x_0 - x', y_0 - y') F(x_0, y_0) F^*(x', y')$$
$$\times U(x - x_0, y - y_0) U^*(x - x_0, y - y_0)$$
$$- y_0') dx_0 dx_0' dy_0 dy_0', \quad (31)$$

where $U(x, y)$ is the impulse response given by, e.g., relation (23) and $\mu(x_0, y_0)$ is the mutual coherence function (see Ref. 1, Sec. 10.5.3). This function is derived from the
source intensity function with the aid of the Zernike–van Cittert theorem, according to
\[ \mu(x_0, y_0) = \frac{\int \int I(p, q) \exp[i(px_0 + i q y_0)] dp dq}{\int \int I(p, q) dp dq}, \]  
(32)

where \( I(p, q) \) is the intensity distribution of the source, observed on the exit pupil sphere of the imaging system; \((x_0, y_0)\) are general normalized coordinates in the image plane.

In the case of a standard illumination function with circular symmetry, the coherence factor \( \sigma \), which gives the ratio between the source radius and the exit pupil radius, is commonly used. In this case, the mutual coherence function is given by the circularly symmetric function
\[ \mu(v) = \frac{2J_1(\sigma v)}{\sigma v}. \]  
(33)

We note that other commonly used illumination modes such as quadrupole, annular, or decentered source configurations lead to comparable analytical mutual coherence functions \( \mu(x_0, y_0) \).

We will now analyze some situations that are frequently encountered in optical lithography, ranging from coherently illuminated objects to the case of full incoherence in the illumination. Note that in our analysis the value of \( \sigma \) is not limited to unity but can be extended to values \( \sigma \gg 1 \).

A. Coherent Imaging

In high-resolution optical lithography, one often enhances the imaged features by manipulating phase structures on the mask. In the case of a fairly coherent imaging process \( \sigma \ll 1 \), phase-shifting features on the mask are most effective; the fully coherent case with \( \sigma = 0 \) is then a fair approximation [the source is a delta function: \( I(p, q) = \delta(p, q) \)]. The corresponding mutual coherence function \( \mu(x_0, y_0) \) equals unity, and the image-plane intensity is given by
\[ I(x, y) = |F(x_0, y_0) \otimes U(x_0, y_0)|^2. \]  
(34)

B. Incoherent Imaging

In optical lithography, the imaging of a so-called binary mask requires a value of \( \sigma \approx 1 \), and the imaging process can be approximated by the fully incoherent case \( \sigma = \infty \), where the source intensity equals unity up to infinity. The mutual coherence function now becomes a delta function, i.e., \( \mu(x_0, y_0) = \delta(x_0, y_0) \), and the image intensity distribution is given by
\[ I(x, y) = |F(x_0, y_0)|^2 \otimes |U(x_0, y_0)|^2. \]  
(35)

This results in an optical system that is now linear in intensity.

C. Partially Coherent Imaging

We now simulate the lithographic imaging process by means of a sequence of spatial delta functions that have imaging properties similar to those of contact holes. The exact shape of small contact holes is not very important; it is the area that determines their relative weight in the imaging process. Therefore we approximate an array of contact holes by an array of delta functions, each having a complex amplitude:
\[ F(x_0, y_0) = \sum n A_n \delta(x_0 - a_n, y_0 - b_n). \]  
(36)

Using Eq. (31), we obtain the image-space intensity distribution
\[ I(x, y) = \sum_{n,m} A_n A_m^* \mu(a_n - a_m, b_n - b_m) \times U(x - a_n, y - b_n) U^*(x - a_m, y - b_m). \]  
(37)

Here the image formation is essentially a nonlinear process, and it cannot be written in terms of a convolution.

In Fig. 4, we present the results of applying Eq. (37) to the configuration of two closely spaced contact holes with a separation of 0.2 μm in an opaque mask. The aerial image intensity is depicted according to the analytical approach. One contact hole is considered to introduce a phase shift of \( \pi \). For this reason, the intensity exactly midway between the two holes is zero in the coherent case. As the coherence of the imaging is decreased \( (\sigma \text{ increases}) \), the interference term weighted by \( \mu(2a, 0) \) gradually vanishes and the individual intensity profiles corresponding to each object merge. In the figure, we have also depicted the intensity profiles produced by the software package SOLID-C, which here used finite-size contact holes as the input pattern (circular holes with a diameter of 100 nm). From Fig. 4, one concludes that the approximation of the contact holes by means of a mathematical delta function is fully justified here; in each figure, the deviations between the analytical and SOLID-C curves do not exceed the typical value of 0.01. The advantage of the analytical approach is the clear relationship between the interfering terms that generate the final image intensity pattern. During the design process of, e.g., phase- and amplitude-assisted masks, a valuable insight is obtained into the relationship between the modulation depth and steepness of the image intensity pattern and the parameter choices for the mask transmission function. The extension to larger arrays of contact holes and the inclusion of defocus and aberrations are straightforward. In each case, starting with the fully coherent case, the interference effects can be studied by using the analytical expression for the complex amplitude. The behavior in the partially coherent case is then obtained as an intermediate situation between the fully coherent and the incoherent case.

6. IMPULSE RESPONSE IN THE PRESENCE OF HIGH-FREQUENCY ABERRATION TERMS

In this section, we present a computational result that is related to a high-frequency wave-front perturbation. It frequently occurs in practice that the wave-front aberration cannot be adequately described by the standard se-
ries of low-frequency Zernike polynomials. These Zernike polynomials are capable of describing the wave fronts emerging from an optical system toward the axial and off-axis field points. Alternatively, if an optical system suffers from a lack of rotational symmetry due to minute tilting and centering errors of the constitutive elements, the wave front converging to an image point on axis shows small basic residual aberration terms that can also be easily represented by means of lower-order Zernike coefficients. On the other hand, manufacturing imperfections of the optical surfaces, spherical or aspherical, may turn up in the wave front emerging from the optical system as higher-frequency components in the wave-front expansion that are outside the scope of the standard series of Zernike polynomials. These high-frequency wave-front perturbations also constitute a serious problem in the frequently used numerical approach for the calculation of the diffraction image that is based on the FFT method. Quickly varying patterns in the pupil function of the optical system complicate the sampling of the pupil function. Moreover, the extent of the diffraction image in the image plane is enlarged by the high-frequency content in the pupil function, and this requires many more sampling points in the image plane. In practice, the number of required sampling points in pupil and image plane may exceed practical values such as $2^{10}$ or, ultimately, $2^{12}$ in one dimension.

When using our approach based on the expansion of the complex pupil function in terms of Zernike polynomials, we exploit the simple relationship of Eq. (5) to translate...
the presence of a Zernike polynomial of radial order \( n \) into an image-plane amplitude distribution given by a function of the type \( J_{n+1}(v)/v \) (no defocusing). In the defocused case, the functions \( V_{n,m} \) from relation (23) are needed.

In Fig. 5, we present a calculated intensity pattern in the presence of a set of high-frequency Zernike coefficients up to order \( n = 25 \), which, in total, produce an rms wave-front aberration of 1/(2\( \pi \)) = 0.159a. The low-intensity part of the calculated pattern outside the central lobe resembles a speckle pattern; this can be explained by the uncorrelated nature of the high-order Zernike coefficients \( \alpha_{n,m} \). Of each polynomial contribution \( \alpha_{n,m}Z_n^m(p, \theta) = \alpha_{n,m}R_n^m(p)\cos m\theta \).

### 7. CONCLUSION

We have implemented our extended Nijboer–Zernike analysis for the calculation of the diffraction point-spread function in the case of both small and large aberration values. Throughout the analysis, the defocusing effect is taken as an independent parameter that can be incremented to several focal depths without any convergence problems. The number of required terms in the series expansion for the complex amplitude in the image space can be estimated by means of some simple expressions that comprise the value of the aberration terms or the defocusing parameter. In practice, the typical number \( L \) of terms needed amounts to 25, yielding an accuracy of 10\(^{-5} \) in the image-plane intensity, while an extension of \( L \) to 40 brings us below the 10\(^{-10} \) value. Various comparisons with numerically based integration schemes have been carried out, showing that an accuracy in intensity in the region 10\(^{-5} \)–10\(^{-3} \) is typical for these methods. This demonstrates that our analytical approach also has the capability of serving as a reference for these numerical methods.

The application of the analysis to the impulse response of an optical system leads to effective calculation schemes in which one can fully exploit the separation of radial and azimuthal dependence in the expressions. We can easily extend our analysis to the case where the wave-front aberration is accompanied by a nonuniform amplitude distribution in the exit pupil of the optical system. An extension to the vectorial treatment of diffraction phenomena at high values of the numerical aperture has not been carried out so far, but the basic approach can equally be applied in this case, the main difference being the number of diffraction integrals to be evaluated (six instead of one).

We have studied not only the image of a point object but also the imaging of extended objects that are illuminated in a general, partially coherent manner. The analytical expressions permit a separate inspection of the various terms contributing to the complex image amplitude. This possibility can be exploited for the effective design of more complicated object structures, e.g., phase- and amplitude-shifting masks in optical microlithography. Moreover, we think that our method presents a serious advantage when dealing with high-frequency aberration terms. The sampling problem in pupil and image plane encountered in, e.g., the FFT approach is absent when using our analytical expressions.

### APPENDIX A: DEFOCUSING TERM AS A FUNCTION OF NUMERICAL APERTURE

In Fig. 6, a spherical wave front through \( P \) converges toward the real image point \( M_2 \). The defocused image is captured in a plane through \( M_1 \), and the axial defocus distance is \( z \). The wave-front deviation \( W_f \) as a function of defocus is given by the optical distance \( PM_1M_2 \):

\[
(W_f + R_1)^2 + z^2 + 2(W_f + R_1)z\cos p = R_2^2. \tag{A1}
\]

Using the property that, for all realistic situations, the wave-front deviation \( W_f \) is much smaller than \( R_1 \), we obtain

\[
W_f = z(1 - \cos p) = z[1 - (1 - \sin^2 p)^{1/2}]. \tag{A2}
\]

The normalized coordinate on the exit pupil sphere through \( O \) and \( P \) is given by the ratio of the sine of a general ray and the sine of the marginal ray, \( \rho = (\sin p)\bar{s}_0 \), where \( s_0 = \sin p_0 = NA \), and the wave-front deviation \( W_f \) now becomes

\[
W_f = z\left(\frac{\sin^2 p}{2} + \frac{\sin^4 p}{8} + \frac{\sin^6 p}{16} + \cdots\right) = \frac{1}{2}z\bar{s}_0^2\rho^2 + \frac{1}{8}z\bar{s}_0^4\rho^4 + \frac{1}{16}z\bar{s}_0^6\rho^6 + \cdots. \tag{A3}
\]

The complete phase term for defocus is obtained by multiplying \( W_f \) with the wave number \( k = 2\pi/\lambda \).

Equation (A3) shows that for larger values of \( NA = s_0 \) at the image side, the defocusing term resulting from the wave-front deviation \( W_f \) is not well approximated by \( \frac{1}{2}kz\bar{s}_0^2\rho^2 \). A considerable enhancement is obtained by replacing \( 1 - (1 - \sin^2 p)^{1/2} \) in Eq. (A2) by its least-squares quadratic approximation \( \bar{b}_0 + \bar{b}_1\rho^2 \). This then leads to the optimal second-order approximation

\[
W_f = z(\bar{b}_0 + \bar{b}_1\rho^2) \tag{A4}
\]

and a corresponding approximation \( kz(\bar{b}_0 + \bar{b}_1\rho^2) \) for the defocusing term. It thus turns out that we obtain aver-
age approximation errors having at $s_0 = 0.82$ the same value as which we would obtain for $s_0 = 0.60$ when we approximate $1 - (1 - \sin^2 \rho)^{1/2}$ by $\frac{1}{2} s_0^2$.

A further extension of this methodology, allowing even higher values of $s_0$, is to develop the remaining approximation error $1 - (1 - \sin^2 \rho)^{1/2} \approx \delta_0 - \delta_1 \rho^2$ in a series involving the radial Zernike polynomials $R_{2n}^m(\rho)$ with $n = 2, 3, \ldots$ and to incorporate this error into the aberration phase $\Phi$. One has, in fact, with $\rho = (\sin \phi) s_0$ as above,

$$
(1 - \sin^2 \rho)^{1/2} = \frac{1}{2}(1 - c_0) \sum_{n=0}^\infty \frac{1}{2n - 1} \left( \frac{1 - c_0}{1 + c_0} \right)^{n-1} - \frac{1}{2n + 1} \left( \frac{1 - c_0}{1 + c_0} \right)^n R_{2n}^0(\rho),
$$

where $c_0 = \cos \rho_0$. The terms with $n = 3, 4, \ldots$ on the right-hand side are sufficiently small for values of $\rho_0 = s_0$ as large as 0.90 that they can be considered small aberrations ($/\rho$) as large as 2$\pi$.

Although the correct representation of the defocus term at high values of $\rho_0$ is important, it is not a sufficient extension to correctly describe the impulse response in this regime. The radiometric effects within the high-NA beam have to be taken into account. By adopting a complex-valued parameter $f$, we can accommodate these radiometric amplitude variations on the pupil sphere. Of course, in a final step, the vectorial treatment of wave propagation as described in Ref. 2 has to be used.

**APPENDIX B: ANALYSIS OF $V_{nm}$ AND $T_{nm}$**

1. **Bounds on $V_{nm}$ and $T_{nm}$**

The following hold for all $f, \nu, v$, and all allowed $n, m$:

$$
|V_{nm}| \leq \frac{M_m(v)}{2n + 1}, \quad |T_{nm}| \leq \frac{M_m(v)}{2n + 2},
$$

where

$$
M_m(v) = \max_{0 < u < v} |J_m(u)| \leq 1.
$$

The bounds in relations (B1) follow easily from the integral representations in Eqs. (8) and (15), where, for the first bound, we also use that

$$
\int_0^1 \rho |R_{2n}^m(\rho)|^2 d\rho = \frac{1}{2(n + 1)},
$$

together with the Cauchy–Schwarz inequality.

2. **Truncation of Infinite Series**

We consider the series representations (9) and (16) of $V_{nm}$ and $T_{nm}$ for the range of $f, \nu, v, n, m$, and $(p, q)$ indicated in relations (12). The main result is as follows. In the relevant range, it is sufficient to include the first 25 terms of the infinite series over $l$ to guarantee absolute accuracy of order $10^{-6}$. Moreover, the truncation errors are in all cases of the same order of magnitude as or smaller than the truncation error for the series

$$
V_{00} = T_{00} = \exp(i f) \sum_{l=1}^\infty (-i f)^l J_l(v) / v^l.
$$

Let us first consider the convergence behavior of the series in Eq. (B4). It follows from the basic properties of the Bessel functions, such as expression 9.1.30 in Ref. 6, that $-i f J_l(v)$ is positive and decreasing in $v \in [0,20]$ when $l \geq 20$. Hence the series in Eq. (B4) exhibits worst-case convergence behavior at $v = 0$, where we have

$$
\frac{J_l(v)}{v^{l}} \bigg|_{v = 0} = \frac{2^{l}}{l!},
$$

so that

$$
V_{00}(v = 0) = \frac{1}{2} \exp(i f) \sum_{l=1}^\infty \frac{(-i f)^l}{l!}.
$$

The convergence analysis of the series in Eq. (B6) can be given by using Stirling’s formula for $l!$! have modulus of order less than unity from $l = [ef]$ onward. For $f = 2 \pi$ we have $[ef] = 17$, and $2^{l-l!}$ decreases from $6 \times 10^{-4}$ at $l = 20$ to $9 \times 10^{-7}$ at $l = 25$. As a rule of thumb, we get that the number $L$ of terms to be included should be somewhat larger than $ef$; normally, $L \approx 3f$ suffices.

We next compare the convergence behavior for the general cases $V_{nm}, T_{nm}$ with that of the standard series $V_{00}, T_{00}$. Here it is enough to restrict attention to $V_{nm}$. This is possible, since one gets from Eqs. (10) and (17) that

$$
|l^{-1} v_{ij}| = \frac{(l - 1)!}{q!} \frac{(q + j)!}{(l - 1 - p + j)!}, \quad j = 0, \ldots, p,
$$

and the right-hand side of Eq. (B7) is 1 for all $l, p, q$ that satisfy $l - 1 - p \geq q$. We shall thus consider the quantity [see Eqs. (9) and (B4)]

$$
Q_{ij} = \left| l^{-1} v_{ij} J_{l+m+2j}(v) / J_l(v) \right|, \quad j = 0, \ldots, p,
$$

and our aim is to bound $\sum_{j=0}^p Q_{ij}$.

Noting that $l$ is large compared with $m, j, q$, we have from Eq. (10) and the definitions of $p$ and $q$ that

$$
|l^{-1} v_{ij}| \approx \frac{(l + m + j)!(l - 1 + j)!}{(l + q + j)!(l - 1 + j - p)!} \left( \frac{p}{q} \right)^j.
$$

Furthermore, there is the inequality

$$
0 \leq J_{s-1}(v) \leq \frac{v/s}{1 + (1 - (v/s)^2)^{1/2}}, \quad 0 \leq v \leq s.
$$

The latter inequality follows from Ref. 6, second formula in expression 9.1.73, for the continued-fraction expansion of $J_1(v) / J_{s-1}(v)$, combined with the continued-fraction expansion

$$
V_{00} = T_{00} = \exp(i f) \sum_{l=1}^\infty (-i f)^l J_l(v) / v^l.
$$
\[
\frac{1}{2} - \left( \frac{1}{4} - c \right)^{1/2} = \frac{c}{1 - 1 - 1 - \cdots}, \quad 0 \leq c \leq \frac{1}{4}.
\]

By applying relation (B10) repeatedly, we thus get that
\[
0 \leq \frac{J_{l+m+2j}(v)}{J_l(v)} \leq b^{m+2j}, \quad 0 \leq v \leq l,
\]
where
\[
b = \frac{v/(l + 1)}{1 + (1 - [v/(l + 1)])^{1/2}}. \tag{B13}
\]

Combining relations (B9) and (B12) and using \(m = q - p\), we get
\[
\sum_{j=0}^{p} Q_{lj} \leq \exp\left[-(q + 1)p/l\right] \sum_{j=0}^{q} \left( \frac{q + j}{p} \right) b^{q-p+2j}. \tag{B14}
\]

The maximum over \(p = 0, \ldots, q\) of the series on the right-hand side of relation (B14) occurs at \(p = q\). A numerical inspection of the quantity
\[
\exp\left[-(q + 1)/l\right] \sum_{j=0}^{q} \left( \frac{q + j}{q} \right) b^{2j} \tag{B15}
\]
for the worst case \(l = 24, v = 20\) (so that \(b = 1/2\)), and \(p = q = 0,1, \ldots, 6\) yields a bound of order 10 for the left-hand side of relation (B14). This is sufficient for our purposes.

We have observed numerically that the absolute-convergence behavior of the series for \(V_{nm}\) is actually better than what one might expect from the foregoing analysis. The reason for this is that some of the estimates [in particular, relation (B12)] are crude, while the various worst cases do not occur simultaneously.

We may note that the truncation analysis can be extended to the cases of different ranges for the various parameters and variables. This is based on the observation that
\[
\sum_{j=0}^{q} \left( \frac{q + j}{q} \right) b^{2j} = P_q(1 + 2b^2)
\]
\[
\approx \frac{(b + \sqrt{1 + b^2})^{2q+1}}{2(\pi bq)^{1/2}(1 + b^2)^{1/4}}, \tag{B16}
\]
where \(P_q\) is the Legendre polynomial of degree \(q\), with asymptotic behavior as given in Ref. 10, theorem 8.2.1. Accordingly, one finds that for large \(l\) the worst-case quantity in expression (B15) behaves like \(\exp[-(q + 1/2)(q + 1/2 - v)/l]\).

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